承 認 書

SPECIFICATION FOR APPROVAL

CUSTOMER: _____

DESCRIPTION: WIRE WOUND CHIP INDUCTOR

Cybermax PART NO: CMCW1005FR56KST

CUSTOMERMODELNO: _____

DRAWING			CUSTOMER APPROVE
MADE	CHECKED	APPROVED	
曹春宁	张有涛	陈启善	
DATE:	2019年07月08日		

cybermax
cybermaxtech.com

CUSTOMER:		REV NO:	A1.0
DESCRIPTION:	WIRE WOUND CHIP INDUCTOR	PAGE NO:	PAGE 1 OF 6
PART NO:	CMCW1005FR56KST	SN.	
CUSTOMER NO:		DATE:	2019 年 07 月 08 日

变更履历

日期	版本	修订内容	制定	核准
2019-07-08	A1.0	新版发行	曹春宁	陈启善

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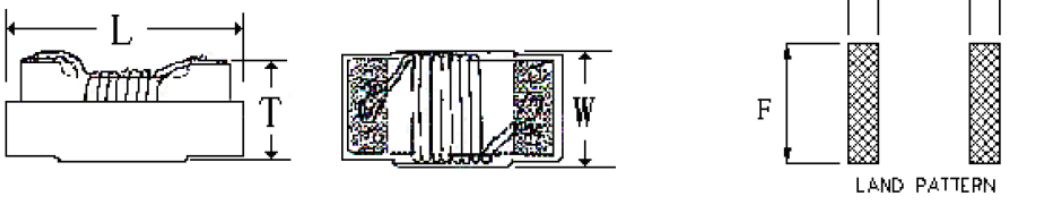
UNIT:mm



CODE	L	W	T	E	F	D	
DIMENSION	1.19MAX	0.66MAX	0.64MAX	0.40Typ.	0.64Typ.	0.64Typ.	

2. ELECTRICAL CHARACTERISTICS @25℃

ITEM	SPEC. RANGE	TEST CONDITION	TEST INSTRUMENTS
L(nH)	560±10%	7.9MHz/0.5V	HP4286A
DCR(Ω)	1.2 MAX		502BC
Irms(mA)	200 MAX		VR116+VR7210
SRF	600 MIN		E5071C ENA

3. PART NUMBERING SYSTEM

CMCW □□□□ □□ □R□ □ □ □

2 3 4 5 6 7

1 PRODUCT SYMBOL（产品代号）

2 DIMENSIONS （规格尺寸）

3 MATERIAL （芯片类型）

4 INDUCTANCE（电感量）

5 TOLERANCE（公差）：F±1%；G±2%；J±5%；K±10%；M±20%

6 TERMINAL （端电极材料）： G-金端头；S-锡端头；Y-银钯端头

7 PACKAGING （包装方式）：T-编带盘装；B –散装

APPROVED BY	CHECKED BY	DRAFT
陈启善	张有涛	曹春宁

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TEST	L	DCR		L	W	T	
ITEM	(nH)	(Ω)		(mm)	(mm)	(mm)	
CON.	7.9MHz/0.5V	At 25℃		1.19MAX	0.66MAX	0.64MAX	
SPEC.	560±10%	1.20 MAX					
1	561.29	0.92		1.07	0.64	0.56	
2	559.97	0.93		1.08	0.63	0.55	
3	558.96	0.92		1.09	0.62	0.56	
4	561.13	0.93		1.08	0.63	0.54	
5	560.37	0.92		1.07	0.64	0.55	
6	559.86	0.94		1.09	0.62	0.56	
7	560.26	0.92		1.08	0.64	0.54	
8	560.26	0.93		1.07	0.63	0.55	
9	559.89	0.93		1.09	0.64	0.56	
10	559.96	0.93		1.08	0.63	0.54	
X	560.2	1.55		1.08	0.63	0.55	
R	2.33	0.03		0.02	0.02	0.02	

图示：

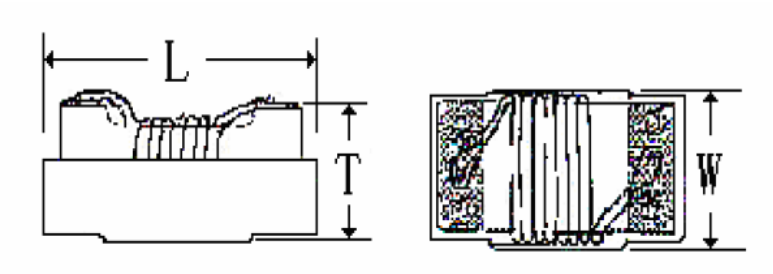

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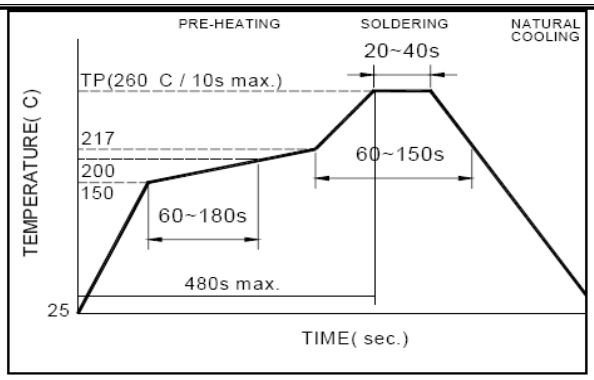
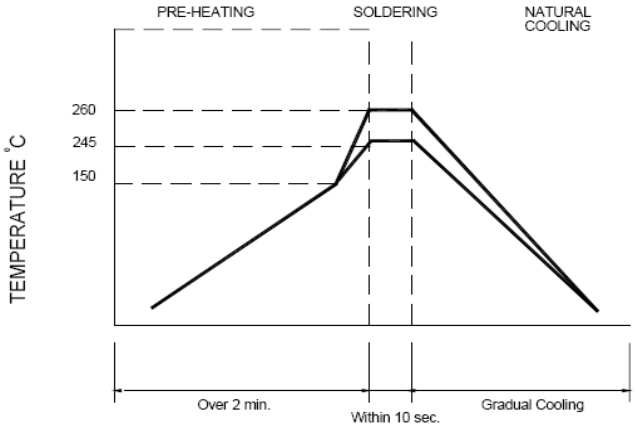
Figure 1.
Re-flow Soldering (Lead Free)



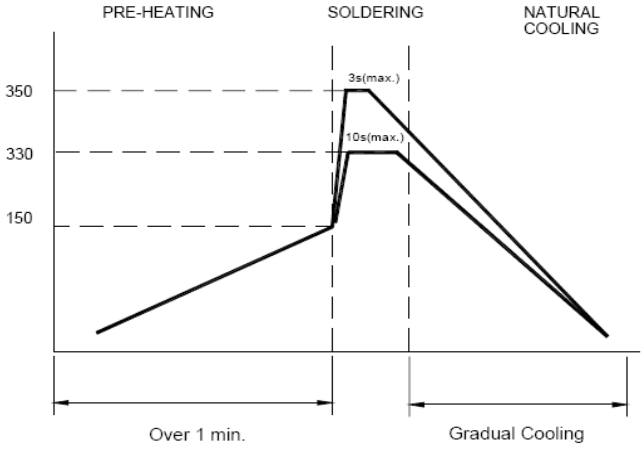
Note:
- Preheat circuit and products to 150℃
- 280℃ tip temperature (max)

Figure 2.
Wave Soldering



Note：
- Never contact the ceramic with the iron tip
- 1.0mm tip diameter (max)

Figure 3.
Hand Soldering



Note:
- Use a 20 watt soldering iron with tip diameter of 1.0mm
- Limit soldering time to 3 sec.

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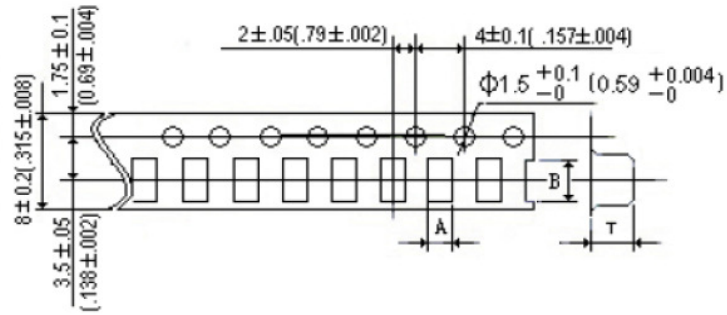
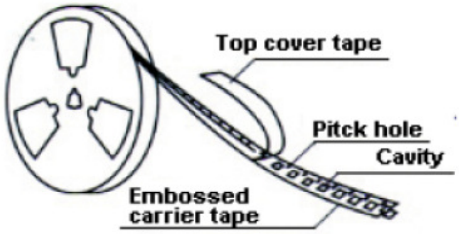
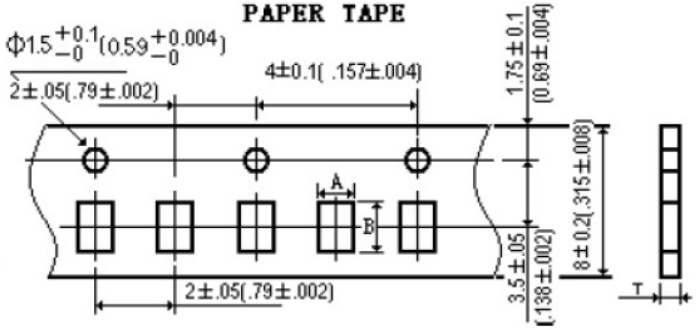
Tape

POLYSTYRENE TAPE

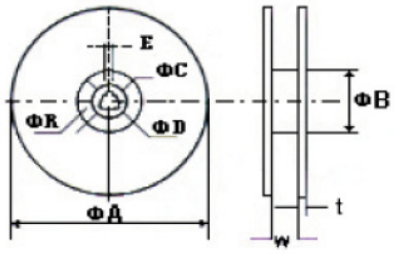




PAPER TAPE



Reel Dimensions



		A	B	T
纸带	0402	0.74	1.23	0.60
胶带	0603	1.15	1.83	0.95
	0805	1.85	2.40	1.45
	1008	2.73	2.90	2.34
	1210	2.96	3.60	2.40
	1812	3.22	4.82	3.15

unit:(mm)

unit	ΦA	ΦB	ΦC	ΦD	E	W	t	R
mm	178	60	13	21	2	10	2	1
	330	75	13	23	2	12	2	1

包装数量

Packaging Quantity

规格 Dimension	0402	0603	0805	1008	1210	1812
数量 Quantity(pcs)	10000	4000	3000	2000	2000	2000

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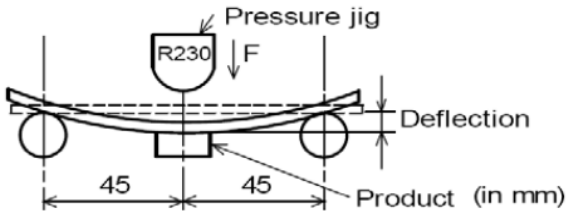
High Temperature Storage	No eviden ce of mechanical damage Inductance change,less than±5% Q chanqe less than±10%	Test Temperature:125±2℃(Ceramic core)85±2℃(Ferrite core) Test Time:96±2Hours
Low Temperature Storage	No eviden ce of mechanical damage Inductance change,less than±5% Q chanqe less than±10%	Test Temperature:-40±2℃ Test Time:96±2Hours
Moisture Resistance	No eviden ce of mechanical damage Inductance change,less than±5% Q chanqe less than±10%	Test Temperature:50±2℃ Test Time:100Hours 相对湿度90~95%
Vibration	No eviden ce of mechanical damage Inductance change,less than±5% Q chanqe less than±10%	Amplitude:1.5mm X、Y、Z方向各1Hours45min Frequency range:10~55~10Hz(min)
Component Adhesion	No eviden ce of mechanical damage No evidence of peel off or broken Keep coutinuity of Winding	Force:2Kgf Test Time:5±1秒
Resistance to bend	No evidence of mechanical damage	Camber:20mm Test Board:Glass-Epoxy board Thickness:8mm 
Life	No eviden ce of mechanical damage Inductance change,less than±5% Q chanqe less than±10%	Test Temperature:85±2℃ Test Time:1000Hours with rating current Test Time:96±2Hours

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